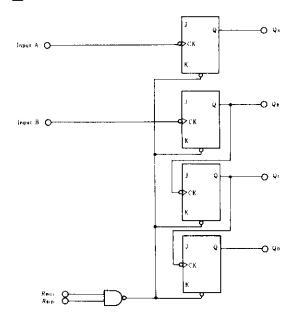
The HD74LS93 contains four master-slave flip-flops and additional gating to provide a divide-by-two counter and three-state binary counter for divide-by-eight. To use this maximum count length of this counter, the B input is connected to the $\mathbf{Q}_{\mathbf{A}}$ output. The input count pulses are applied to input A and the outputs are described in the appropriate function table.

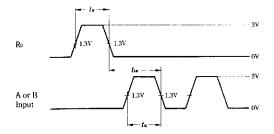
■BLOCK DIAGRAM



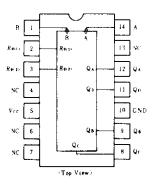
MRECOMMENDED OPERATING CONDITIONS

Ite	n	Symbol	min	typ	max	Unit
Count A input		,	0		32	MIII.
frequency	B input	frount	0	_	16	MHz
	A input	tw	15			
Pulse	B input		30	-	Ī	l ns
width	Reset inputs		15			
Setup time		ts u	25	-		ns

TIMING DEFINITION



■PIN ARRANGEMENT



MADSOLUTE MAXIMUM RATINGS

Item Supply voltage		Symbol	Ratings	Unit V	
		Vec	7.0		
Input	R Inputs	17	7.0	V	
voltage	A, B Inputs	Vin	5.5	v	
Operating temperature range		Topt	-20~ +75		
Storage tem	perature range	Terk	65 + 150	°C	

TUNCTION TABLE

■ Reset/Count Function Table

Reset	Inputs		Out	puts	
R0m	R0(2)	Qυ	Qc	Qв	QA
Н	н	L	L	L	L
L	×		Со	unt	
×	L		Со	unt	

●BCD Count Sequence (Notes 1)

		Out	puts	
Count.	Qп	Qc	Qв	Q_A
0	L	L	L	L
1	L	L	L	Н
2	L	L	н	I.
3	L	L	н	Н
4	L	Н	L	L
5	L	Н	L	Н
6	L	Н	Н	L
7	L	Н	н	Н
8	Н	L	L	L
9	Н	L	L	Н
10	Н	L	Н	L
11	Н	L	Н	Н
12	Н	Н —	L	L
13	Н	Н	L	Н
14	Н	Н	Н	L
15	Н	Н	H	Н

Notes) 1. Output $Q_{\mbox{\scriptsize A}}$ is connected to input B for BCD count.

2. H; high level, L; low level, X; irrelevant

ELECTRICAL CHARACTERISTICS ($Ta = -20 \sim +75^{\circ}C$)

Ite	n	Symbol	Test Conditions		min	typ*	max	Unit
		Vin			2.0	_		v
Input voltage		VIL					0.8	v
		Voн	$V_{CC} = 4.75V$, $V_{IH} = 2V$, $V_{IL} = 0.8V$, I _{OH} = -400 µA	2.7	_		v
Output voltage			$V_{CC} = 4.75 \text{V}, V_{IH} = 2 \text{V},$	IoL = 4mA**		_	0.4	v
		Vol	$V_{L}=0.8V$ $I_{OL}=8\text{mA}^{\bullet\bullet}$		_		0.5	V
Any Reset					_	-	-0.4	
Ī	A input	Iπ	$V_{CC} = 5.25 \text{V}, V_I = 0.4 \text{V}$				-2.4	mA
	B input					_	-1.6	
	Any Reset				-		20	
Input current	A input	Іін	$V_{CC} = 5.25 \text{V}, V_{I} = 2.7 \text{V}$			40	μA	
	B input					_	40	
	Any Reset			$V_l = 7 \text{ V}$	_	-	0.1	
	A input	Ī:	$V_{CC}=5.25V$	$V_I = 5.5 \text{V}$		_	0.2	mA
	B input			$V_I = 5.5 \text{V}$	_	_	0.2	
Short-circuit output current R		los	$V_{CC} = 5.25 \text{V}$		- 20		-100	mA
Supply current		Icc***	$V_{CC} = 5.25 \text{V}$		_	9	15	mA
Input clamp volta	ige	Vik	$V_{CC} = 4.75 \text{V}, I_{LN} = -18 \text{mA}$		-	_	-1.5	V

ESWITCHING CHARACTERISTICS ($V_{CC} = 5V$, $T_a = 25^{\circ}C$)

Item	Symbol	Inputs	Outputs	Test Conditions	min	typ	max	Unit
		A	QA		32	42	_	MHz
Maximum count frequency	fmax.	В	Qв		16		-	
	telh .				-	10	16	
	tphl	A	Q _A	$C_L = 15 \mathrm{pF}, R_L = 2 \mathrm{k}\Omega$	-	12	18	ns
	tPLH	A	Qυ		-	46	70	ns
	tphl				_	46	70	
	tрін	В	B Q _B		_	10	16	ns
Propagation delay time	tphi.				_	14	21	
	tplh				_	21	32	
	tрнL	В	Q _C			23	35	
	tplн				-	34	51	
	tphl	В	Q□	•	_	34	51	ns
	<i>t</i> PHL	Set-to-0	QA~QD		_	26	40	ns

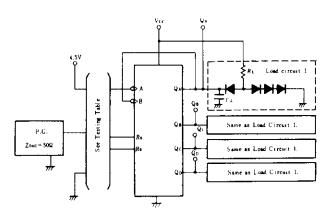
^{*} V_{CC}=5V, Ta=25°C

* Q_A output is tested at specified I_{OL} plus the limit value of I_{IL} for the B input. This permits driving the B input while maintaining full fan-out capability.

^{***} I_{CC} is measured with all outputs open, both R₀ inputs grounded following momentary connection to 4.5V, and all other inputs grounded.

TESTING METHOD

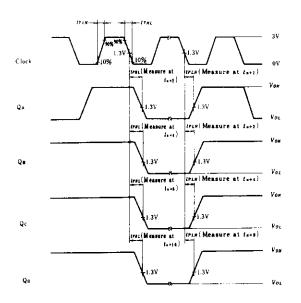
1) Test Circuit



Notes) 1. C_L includes probe and jig capacitance.

2. All diodes are 1S2074 (f).

Waveform-1 fmax. tPLH, tPHL, (Clock→Q)



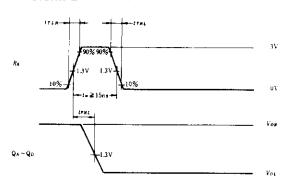
Notes) 1. Input pulse; $t_{TLH} \le 15 \text{ ns}$, $t_{THL} \le 5 \text{ ns}$, PRR = 1 MHz, duty cycle=50% and: for f_{max} , $t_{TLH} = t_{THL} \le 2.5$ ns. 2. t_n is reference bit time when all outputs are low.

2) Testing Table

¥.	From input		Inputs			Outputs			
ltem	to output	Α	В	R₀	QA	Qв	Qc	Qυ	
	A →Q	IN	to QA	GND	Out	Out	Out	Out	
/mar	B →Q	4.5V	IN	GND		Out	Out	Out	
	A →Q _A	IN	to Qa	GND	Out	_	_	_	
	A →Q _D	IN	to QA	GND	_	-		Out	
PLH	B →Q _B	4.5V	IN	GND		Out			
1PHL	B →Qc	4.5V	IN	GND	-		Out		
	$B \rightarrow Q_D$	4.5V	IN	GND	_	_	_	Out	
	R8→Q	IN*	to QA	IN	Out	Out	Out	Out	

^{*} For initialized.

Waveform-2 tPHL(Ro→Q)



Notes) 1. $t_{TLH} \le 15$ ns, $t_{THL} \le 5$ ns.

^{**} Measured with each input and unused inputs at 4.5V.

Unit: mm



Hitachi Code	DP-14
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	0.97 g

Unit: mm

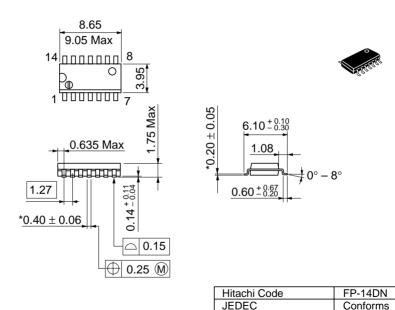


Weight (reference value)

0.23 g

*Dimension including the plating thickness
Base material dimension

Unit: mm



EIAJ

Weight (reference value)

Conforms

0.13 g

*Pd plating

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